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Low-voltage switchgear and controlgear - Part 2: Circuit-breakers (IEC 60947-2:2003)

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<u>SIST EN 60947-2:2003</u> https://standards.iteh.ai/catalog/standards/sist/0f99c21d-5518-4f10-ad8e-

ICS 29.130.20

Referenčna številka SIST EN 60947-2:2003(en)

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EUROPEAN STANDARD

EN 60947-2

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2003

Supersedes EN 60947-2:1996 + A1:1997 + A2:2001

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English version

Low-voltage switchgear and controlgear Part 2: Circuit-breakers (IEC 60947-2:2003)

Appareillage à basse tension Partie 2: Disjoncteurs (CEI 60947-2:2003) Niederspannungsschaltgeräte Teil 2: Leistungsschalter (IEC 60947-2:2003)

This European Standard was approved by CENELEC on 2003-06-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariator to any CENELEC member.

https://standards.iteh.ai/catalog/standards/sist/0f99c21d-5518-4f10-ad8e-This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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Foreword

The text of document 17B/1269/FDIS, future amendment to IEC 60947-2:1995, prepared by SC 17B, Low-voltage switchgear and controlgear, of IEC TC 17, Switchgear and controlgear, was submitted to the IEC-CENELEC parallel vote.

The text of this document, together with that of IEC 60947-2:1995 and its amendments 1:1997 and 2:2001, was published by IEC as the third edition of IEC 60947-2 and was approved by CENELEC as EN 60947-2 on 2003-06-01.

This European Standard supersedes EN 60947-2:1996 + corrigendum June 1997 + A1:1997 + A2:2001.

The following dates were fixed:

_	latest date by which the EN has to be implemented	
	at national level by publication of an identical	
	national standard or by endorsement	(dop) 2004-03-01
_	latest date by which the national standards conflicting	
_	with the EN have to be withdrawn	(dow) 2006-06-01

Annexes designated "normative" are part of the body of the standard. Annexes designated "informative" are given for information only. In this standard, annexes A, B, C, F, G, H, J, L, M, N and ZA are normative and annexes E and K are informative. Annex ZA has been added by CENELEC.

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The text of the International Standard IEC 60947-2:2003 was approved by CENELEC as a European Standard without any modification.

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	<u>EN/HD</u>	Year
IEC 60050-441	1984	International Electrotechnical Vocabulary (IEV) Chapter 441: Switchgear, controlgear and fuses	-	-
IEC 60051	Series iTe	Direct acting indicating analogue electrical measuring instruments and their accessories (standards.iteh.ai)	EN 60051	Series
IEC 60068-2-14	1984	Environmental testing Part 2: Tests - Test N: Change of temperature dards.iteh.avcatalog/standards/sist/0f99c21d-5518-4	EN 60068-2-14 ¹⁾	1999
IEC 60068-2-30	1980	Part 2: Tests ¹ Test Db and guidance: Damp heat, cyclic (12 + 12 hour cycle)	EN 60068-2-30 ²⁾	1999
IEC 60364 (mod)	Series	Electrical installations of buildings	HD 384.1 S2	Series
IEC 60364-4-41	1982	Part 4: Protection for safety – Chapter 41: Protection against electric shock	-	-
IEC 60695-2-10	2000	Fire hazard testing Part 2-10: Glowing/hot-wire based test methods - Glow-wire apparatus and common test procedure	EN 60695-2-10	2001
IEC 60695-2-11	2000	Part 2-11: Glowing/hot-wire based test methods - Glow-wire flammability test method for end-products	EN 60695-2-11	2001
IEC 60695-2-12	2000	Part 2-12: Glowing/hot-wire based test methods - Glow-wire flammability test method for materials	EN 60695-2-12	2001

¹⁾ EN 60068-2-14 includes A1:1986 to IEC 60068-2-14.

²⁾ EN 60068-2-30 includes A1:1985 to IEC 60068-2-30.

Publication	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	Year
IEC 60695-2-13	2000	Part 2-13: Glowing/hot-wire based test methods - Glow-wire ignitability test method for materials	EN 60695-2-13	2001
IEC/TR 60755	1983	General requirements for residual current operated protective devices	-	-
IEC 60898	- 3)	Circuit-breakers for overcurrent protection for household and similar installations	EN 60898 + amendments	1991 4)
IEC 60934	- 3)	Circuit-breakers for equipment (CBE)	EN 60934	2001 5)
IEC 60947-1 (mod)	1999	Low-voltage switchgear and controlgear Part 1: General rules	EN 60947-1 + corr. October	1999 1999
A1 A2	2000 2001		A1 A2	2000 2001
IEC 60947-4-1	2000	Part 4-1: Contactors and motor- starters - Electromechanical contactors and motor-starters	EN 60947-4-1	2001
IEC 61000-3-2 (mod)	20 00 e	Electromagnetic compatibility (EMC) Part 3-2: Limits - Limits for harmonic current emissions (equipment input current up to and including 16 A per phase) SIST EN 60947-2:2003	EN /61000-3-2	2000
IEC 61000-3-3	₩994 ^{/stan}	Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current up to and including 16 A per phase and not subject to conditional connection	^{f1} EN ⁴ 61000-3-3 + corr. July	1995 1997
IEC 61000-4-2	1995	Part 4-2: Testing and measurement techniques - Electrostatic discharge immunity test	EN 61000-4-2	1995
A1 A2	1998 2000		A1 A2	1998 2001
IEC 61000-4-3	2002	Part 4-3: Testing and measurement techniques - Radiated, radio- frequency, electromagnetic field	EN 61000-4-3	2002
A1	2002	immunity test	A1	2002

³⁾ Undated reference.

⁴⁾ EN 60898:1991 and its amendments are superseded by EN 60898-1:2003, which is based on IEC 60898-1:2002, mod.

⁵⁾ Valid edition at date of issue.

Publication	Year	<u>Title</u>	<u>EN/HD</u>	Year
IEC 61000-4-4	1995	Part 4-4: Testing and measurement techniques - Electrical fast transient/burst immunity test	EN 61000-4-4	1995
A1 A2	2000 2001		A1 A2	2001 2001
IEC 61000-4-5	1995	Part 4-5: Testing and measurement techniques - Surge immunity test	EN 61000-4-5	1995
A1	2000	techniques - Surge minimunity test	A1	2001
IEC 61000-4-6	1996	Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio- frequency fields	EN 61000-4-6	1996
A1	2000		A1	2001
IEC 61000-4-11	1994	Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests	EN 61000-4-11	1994
A1	2000		A1	2001
IEC 61000-5-2	1997 iTe	cabling	EW	-
IEC 61008-1 (mod)	1990 https://star	for nousehold and similar uses	EN 61008-1 ⁶⁾ 4f10-ad8e-	1994
		(RCCBର) ^{134b18c/sist-en-60947-2-2003} Part 1: General rules		
IEC 61009-1 (mod)	1991	Electrical accessories - Residual current operated circuit-breakers with integral overcurrent protection for household and similar uses (RCBO's) Part 1: General rules	EN 61009-1	1994
CISPR 11 (mod)	1997	Industrial, scientific and medical (ISM) radio-frequency equipment - Radio disturbance characteristics - Limits and methods of measurement	EN 55011	1998
A1	1999		A1	1999
CISPR 22 (mod)	1997	Information technology equipment - Radio disturbance characteristics - Limits and methods of measurement	EN 55022 + corr. July	1998 2001

⁶⁾ EN 61008-1 includes A1:1992 to IEC 61008-1.

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NORME **INTERNATIONALE INTERNATIONAL STANDARD**

CEI IEC 60947-2

Troisième édition Third edition 2003-04

Appareillage à basse tension –

Partie 2: Disjoncteurs

. . . .

Low-voltage switchgear and controlgear –

Part 2: **Circuit-breakers**

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Commission Electrotechnique Internationale International Electrotechnical Commission Международная Электротехническая Комиссия CODE PRIX PRICE CODE



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

LOW-VOLTAGE SWITCHGEAR AND CONTROLGEAR -

Part 2: Circuit-breakers

FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
- 3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.
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- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60947-2 has been prepared by subcommittee 17B: Low-voltage switchgear and controlgear, of IEC technical committee 17: Switchgear and controlgear.

This third edition of IEC 60947-2 cancels and replaces the second edition published in 1995, amendment 1 (1997) and amendment 2 (2001).

The document 17B/1269/FDIS, circulated to the National Committees as amendment 3, led to the publication of this new edition.

The text of this standard is based on the second edition, its amendments 1 and 2 and the following documents: Teh STANDARD PREVIEW

(sfandard	Report on voting	
17B/1269/FDIS	17B/1278/RVD	
SIST EN 60947-2:2003		

Full information brother voting for the approval of this standard can be found in the report on voting indicated in the above table a 1134b18c/sist-en-60947-2-2003

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2004. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.